

Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 290.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	2450.000, 0	7.77	1.86	40.7

Hardware Setup

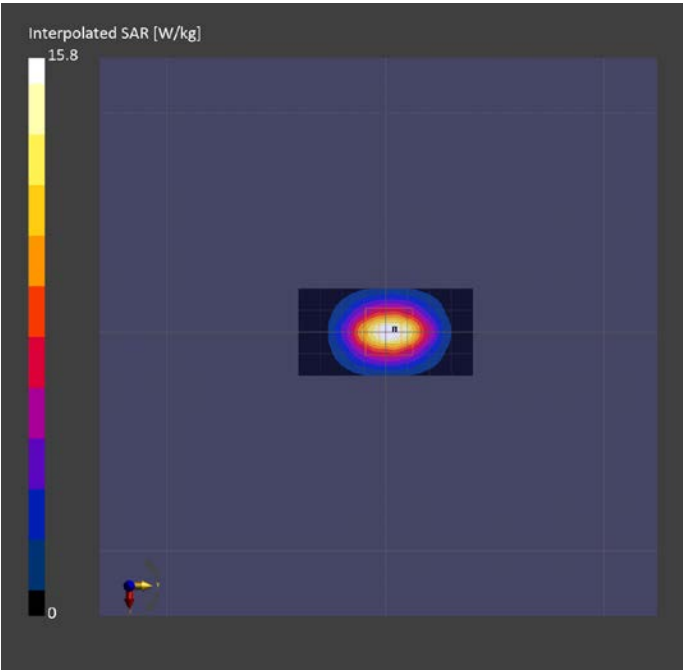
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h2450-260407 , 2026-04-07	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-04-07	2026-04-07
psSAR1g [W/kg]	12.0	12.2
psSAR10g [W/kg]	5.56	5.95
Power Drift [dB]		0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		84.3
Dist 3dB Peak [mm]		9.1



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Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 290.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	2450.000, 0	7.77	1.84	40.2

Hardware Setup

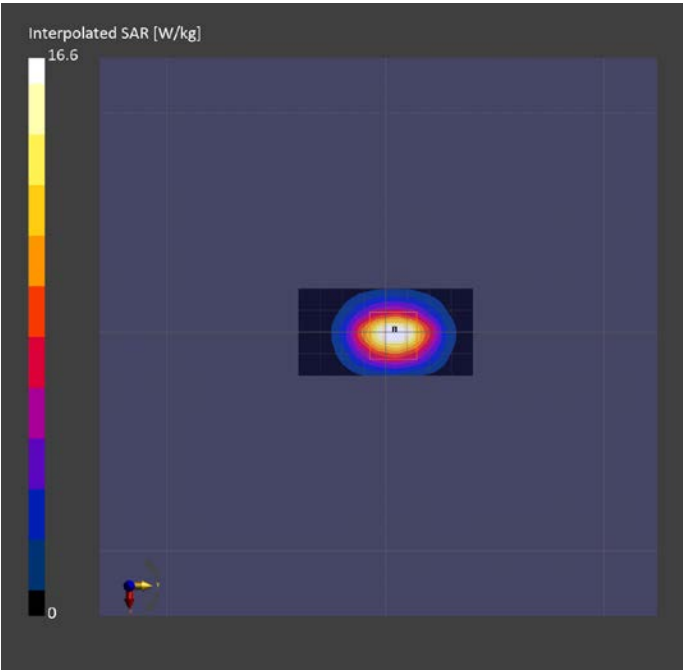
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h2.4G-260410 , 2026-04-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-04-10	2026-04-10
psSAR1g [W/kg]	12.9	13.4
psSAR10g [W/kg]	6.02	6.69
Power Drift [dB]		0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		82.9
Dist 3dB Peak [mm]		9.1



Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 300.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5200.000, 0	6.1	4.54	35.9

Hardware Setup

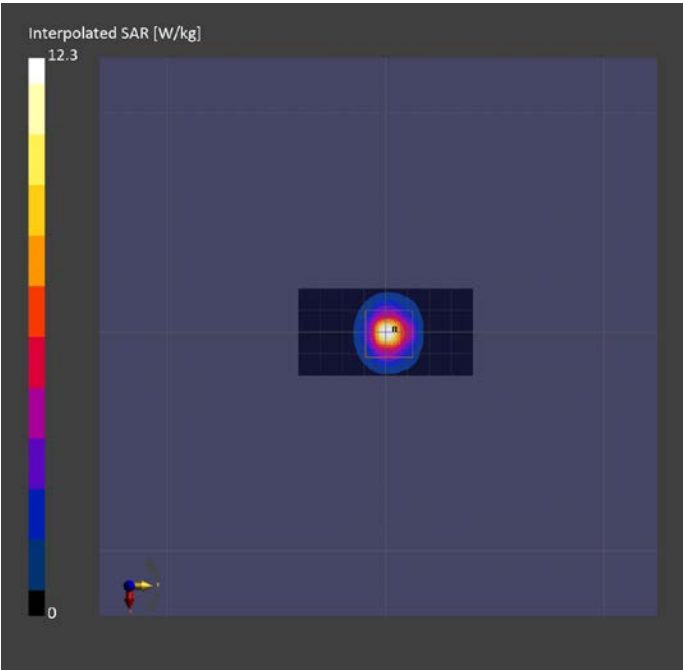
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260409 , 2026-04-09	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-04-09	2026-04-09
psSAR1g [W/kg]	7.54	8.44
psSAR10g [W/kg]	2.17	2.39
Power Drift [dB]		0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		61.3
Dist 3dB Peak [mm]		7.4



Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 300.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5200.000, 0	6.1	4.70	36.4

Hardware Setup

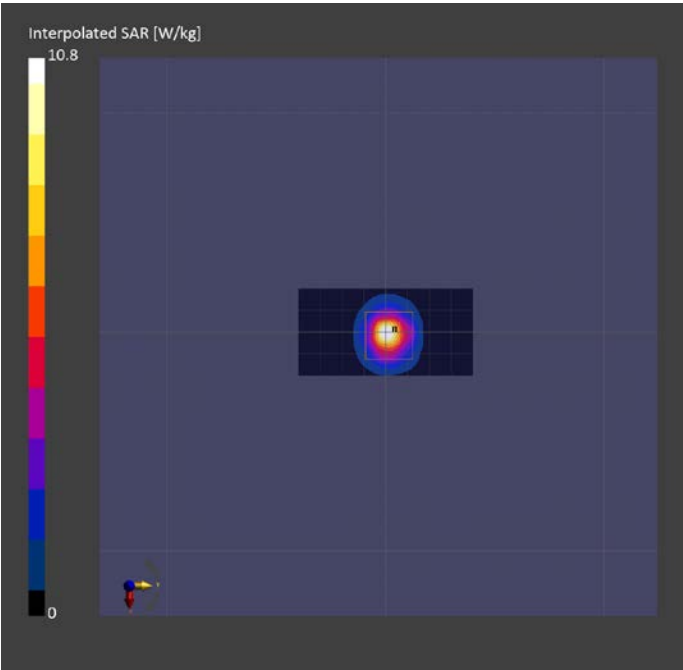
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260410 , 2026-04-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-04-10	2026-04-10
psSAR1g [W/kg]	6.65	7.43
psSAR10g [W/kg]	1.93	2.08
Power Drift [dB]		-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		61.3
Dist 3dB Peak [mm]		7.2



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Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5800.000, 0	5.42	5.23	34.8

Hardware Setup

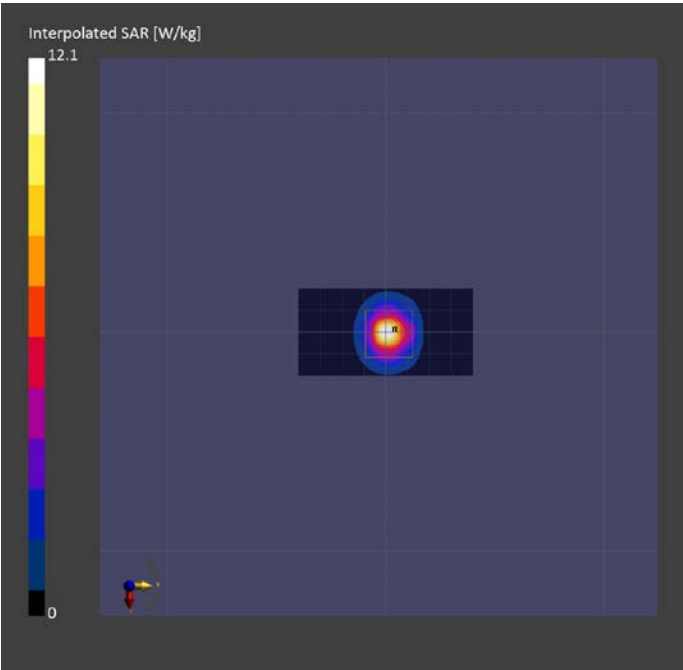
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260409 , 2026-04-09	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-04-09	2026-04-09
psSAR1g [W/kg]	7.64	8.70
psSAR10g [W/kg]	2.17	2.43
Power Drift [dB]		-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		55.5
Dist 3dB Peak [mm]		7.4



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Device under Test Properties

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Device,	10.0 x 10.0 x 300.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5800.000, 0	5.42	5.40	34.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260410 ,2026-04-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

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Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
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Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-04-10	2026-04-10
psSAR1g [W/kg]	7.77	8.84
psSAR10g [W/kg]	2.22	2.45
Power Drift [dB]		0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		55.7
Dist 3dB Peak [mm]		7.3

